

# LM4562 Dual High Performance, High Fidelity Audio Operational Amplifier

# Dual High Performance, High Fidelity Audio Operational Amplifier

## **General Description**

The LM4562 is part of the ultra-low distortion, low noise, high slew rate operational amplifier series optimized and fully specified for high performance, high fidelity applications. Combining advanced leading-edge process technology with state-of-the-art circuit design, the LM4562 audio operational amplifiers deliver superior audio signal amplification for outstanding audio performance. The LM4562 combines extremely low voltage noise density (2.7nV/ $\sqrt{\text{Hz}}$ ) with vanishingly low THD+N (0.00003%) to easily satisfy the most demanding audio applications. To ensure that the most challenging loads are driven without compromise, the LM4562 has a high slew rate of  $\pm$ 20V/µs and an output current capability of  $\pm$ 26mA. Further, dynamic range is maximized by an output stage that drives 2k $\Omega$  loads to within 1V of either power supply voltage and to within 1.4V when driving 600 $\Omega$  loads.

The LM4562's outstanding CMRR (120dB), PSRR (120dB), and  $V_{OS}$  (0.1mV) give the amplifier excellent operational amplifier DC performance.

The LM4562 has a wide supply range of  $\pm 2.5V$  to  $\pm 17V$ . Over this supply range the LM4562's input circuitry maintains excellent common-mode and power supply rejection, as well as maintaining its low input bias current. The LM4562 is unity gain stable. This Audio Operational Amplifier achieves outstanding AC performance while driving complex loads with values as high as 100pF.

The LM4562 is available in 8–lead narrow body SOIC, 8–lead Plastic DIP, and 8–lead Metal Can TO-99. Demonstration boards are available for each package.

## **Key Specifications**

Power Supply Voltage Range

Typical Application

THD+N ( $A_V = 1$ ,  $V_{OUT} = 3V_{BMS}$ ,  $f_{IN} = 1$ kHz)

±2.5V to ±17V

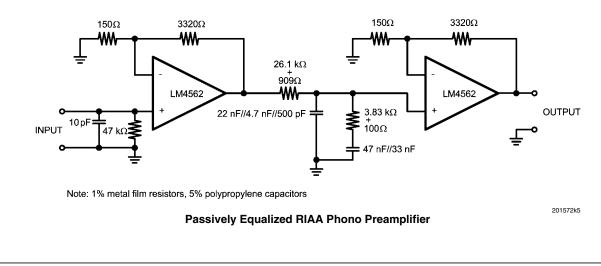
$R_L = 2k\Omega$	0.00003% (typ)
R <sub>L</sub> = 600Ω	0.00003% (typ)
Input Noise Density	2.7nV/√Hz (typ)
Slew Rate	±20V/µs (typ)
Gain Bandwidth Product	55MHz (typ)
<ul> <li>Open Loop Gain (R<sub>L</sub> = 600Ω)</li> </ul>	140dB (typ)
Input Bias Current	10nA (typ)
Input Offset Voltage	0.1mV (typ)
DC Gain Linearity Error	0.000009%

### **Features**

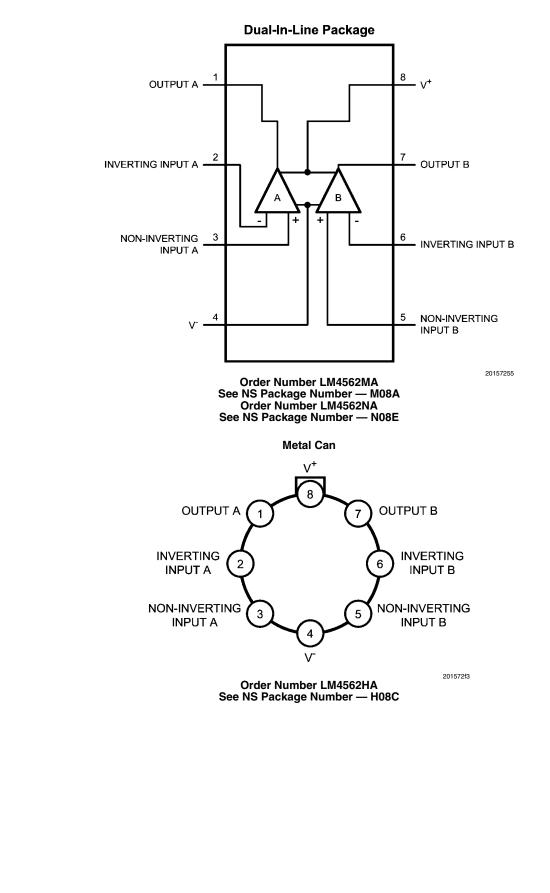
- Easily drives 600Ω loads
- Optimized for superior audio signal fidelity
- Output short circuit protection
- PSRR and CMRR exceed 120dB (typ)
- SOIC, DIP, TO-99 metal can packages

### **Applications**

- Ultra high quality audio amplification
- High fidelity preamplifiers
- High fidelity multimedia
- State of the art phono pre amps
- High performance professional audio
- High fidelity equalization and crossover networks
- High performance line drivers
- High performance line receivers
- High fidelity active filters



### **Connection Diagrams**



### Absolute Maximum Ratings (Note 1, Note

### <u>2</u>)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/

please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.		Thermal Resistance		
Power Supply Voltage	na specifications.	$\theta_{JA}$ (SO)	145°C/W	
$(V_{\rm S} = V^+ - V^-)$	36V	θ <sub>JA</sub> (NA) θ <sub>IA</sub> (HA)	102°C/W 150°C/W	
Storage Temperature Input Voltage	-65°C to 150°C (V-) - 0.7V to (V+) + 0.7V	θ <sub>ις</sub> (HA)	35°C/W	
Output Short Circuit (Note 3)	Continuous	Temperature Range		
Power Dissipation	Internally Limited	$T_{MIN} \le T_A \le T_{MAX}$	$-40^{\circ}\text{C} \le \text{T}_{\text{A}} \le 85^{\circ}\text{C}$	
ESD Susceptibility (Note 4)	2000V	Supply Voltage Range	$\pm 2.5V \le V_S \le \pm 17V$	

ESD Susceptibility (Note 5)

Pins 1, 4, 7 and 8

Pins 2, 3, 5 and 6

Junction Temperature

### Electrical Characteristics for the LM4562 (Note 1, Note 2) The specifications apply for $V_s = \pm 15V$ ,

 $R_L$  = 2k\Omega,  $f_{IN}$  = 1kHz,  $T_A$  = 25°C, unless otherwise specified.

			LM4562		
Symbol	Parameter	Conditions	Typical Limit		Units
			(Note 6)	(Note 7)	(Limits)
THD+N	Total Harmonic Distortion + Noise	$A_{V} = 1, V_{OUT} = 3V_{rms}$ $R_{L} = 2k\Omega$ $R_{L} = 600\Omega$	0.00003	0.00009	% (max)
IMD	Intermodulation Distortion	A <sub>V</sub> = 1, V <sub>OUT</sub> = 3V <sub>RMS</sub> Two-tone, 60Hz & 7kHz 4:1	0.00005		%
GBWP	Gain Bandwidth Product		55	45	MHz (min)
SR	Slew Rate		±20	±15	V/µs (min)
FPBW	Full Power Bandwidth	$V_{OUT} = 1V_{P-P}, -3dB$ referenced to output magnitude at f = 1kHz	10		MHz
t <sub>s</sub>	Settling time	$A_V = -1$ , 10V step, $C_L = 100pF$ 0.1% error range	1.2		μs
_	Equivalent Input Noise Voltage	f <sub>BW</sub> = 20Hz to 20kHz	0.34	0.65	μV <sub>RMS</sub> (max)
e <sub>n</sub>	Equivalent Input Noise Density	f = 1kHz f = 10Hz	2.7 6.4	4.7	nV/√Hz (max)
i <sub>n</sub>	Current Noise Density	f = 1kHz f = 10Hz	1.6 3.1		pAJ√Hz
V <sub>OS</sub>	Offset Voltage		±0.1	±0.7	mV (max)
$\Delta V_{OS} / \Delta Temp$	Average Input Offset Voltage Drift vs Temperature	–40°C ≤ T <sub>A</sub> ≤ 85°C	0.2		μV/°C
PSRR	Average Input Offset Voltage Shift vs Power Supply Voltage	$\Delta V_{\rm S} = 20V$ (Note 8)	120	110	dB (min)
ISO <sub>CH-CH</sub>	Channel-to-Channel Isolation	f <sub>IN</sub> = 1kHz f <sub>IN</sub> = 20kHz	118 112		dB
I <sub>B</sub>	Input Bias Current	$V_{CM} = 0V$	10	72	nA (max)
ΔI <sub>OS</sub> /ΔTemp	Input Bias Current Drift vs Temperature	–40°C ≤ T <sub>A</sub> ≤ 85°C	0.1		nA/°C
l <sub>os</sub>	Input Offset Current	$V_{CM} = 0V$	11	65	nA (max)
V <sub>IN-CM</sub>	Common-Mode Input Voltage Range		+14.1 -13.9	(V+) - 2.0 (V-) + 2.0	V (min)
CMRR	Common-Mode Rejection	-10V <vcm<10v< td=""><td>120</td><td>110</td><td>dB (min)</td></vcm<10v<>	120	110	dB (min)
7	Differential Input Impedance		30		kΩ
Z <sub>IN</sub>	Common Mode Input Impedance	-10V <vcm<10v< td=""><td>1000</td><td></td><td>MΩ</td></vcm<10v<>	1000		MΩ

LM4562

200V

100V

150°C

Symbol	Parameter	Conditions	LM4	LM4562	
			Typical	Limit	Units (Limits)
			( <i>Note 6</i> )	(Note 7)	
		$-10V < Vout < 10V, R_{L} = 600\Omega$	140	125	
A <sub>VOL</sub>	A <sub>VOL</sub> Open Loop Voltage Gain	$-10V$ <vout<10v, r<sub="">L = 2k<math>\Omega</math></vout<10v,>	140		dB (min)
		-10V <vout<10v, <math="">R_L = 10k\Omega</vout<10v,>	140		1
		R <sub>L</sub> = 600Ω	±13.6	±12.5	V (min)
V <sub>OUTMAX</sub>	V <sub>OUTMAX</sub> Maximum Output Voltage Swing	$R_L = 2k\Omega$	±14.0		
		$R_L = 10k\Omega$	±14.1		1
I <sub>OUT</sub>	Output Current	R <sub>L</sub> = 600Ω, V <sub>S</sub> = ±17V	±26	±23	mA (min)
I <sub>OUT-CC</sub>	Instantaneous Short Circuit Current		+53 -42		mA
		f <sub>IN</sub> = 10kHz			
R <sub>OUT</sub>	Output Impedance	Closed-Loop	0.01		Ω
		Open-Loop	13		
C <sub>LOAD</sub>	Capacitive Load Drive Overshoot	100pF	16		%
I <sub>S</sub>	Total Quiescent Current	I <sub>OUT</sub> = 0mA	10	12	mA (max)

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur.

**Note 2:** Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 3: Amplifier output connected to GND, any number of amplifiers within a package.

Note 4: Human body model, 100pF discharged through a 1.5k $\!\Omega$  resistor.

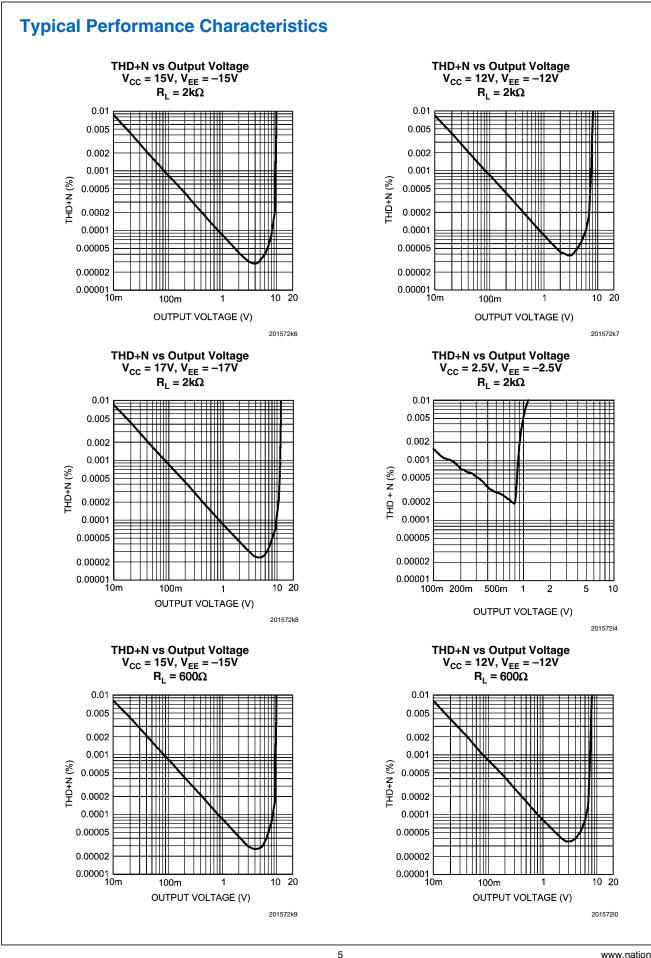
Note 5: Machine Model ESD test is covered by specification EIAJ IC-121-1981. A 200pF cap is charged to the specified voltage and then discharged directly into the IC with no external series resistor (resistance of discharge path must be under 50Ω).

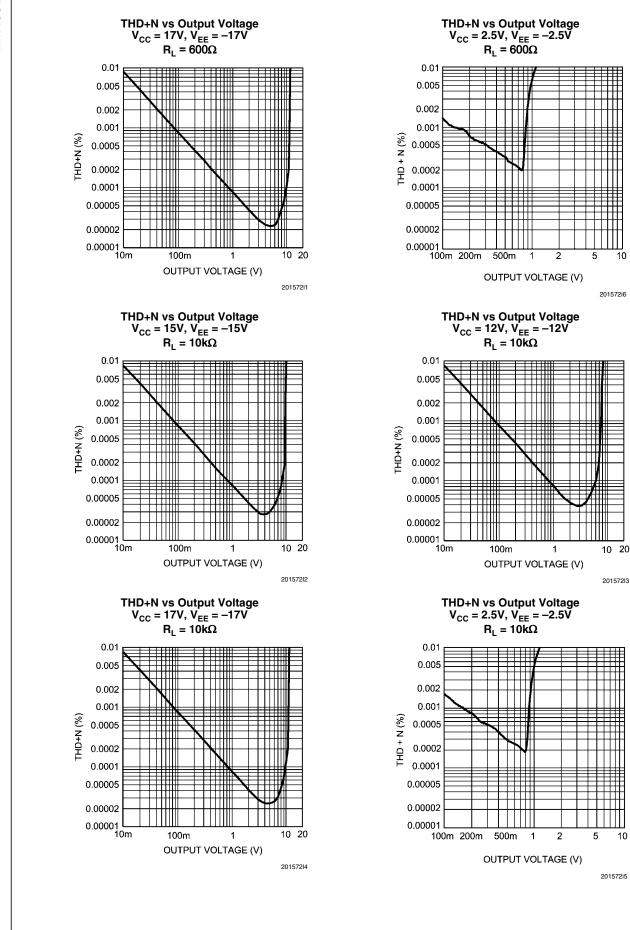
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Note 6: Typical specifications are specified at +25°C and represent the most likely parametric norm.

Note 7: Tested limits are guaranteed to National's AOQL (Average Outgoing Quality Level).

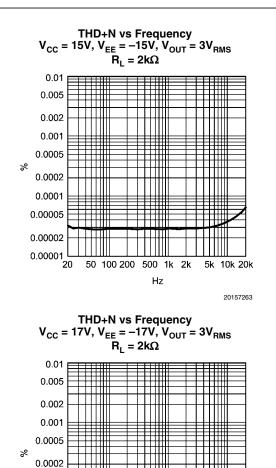
Note 8: PSRR is measured as follows:  $V_{OS}$  is measured at two supply voltages, ±5V and ±15V. PSRR = |  $20log(\Delta V_{OS}/\Delta V_S)$  |.

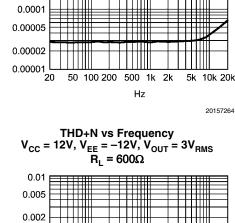


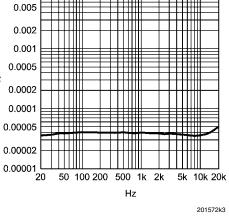


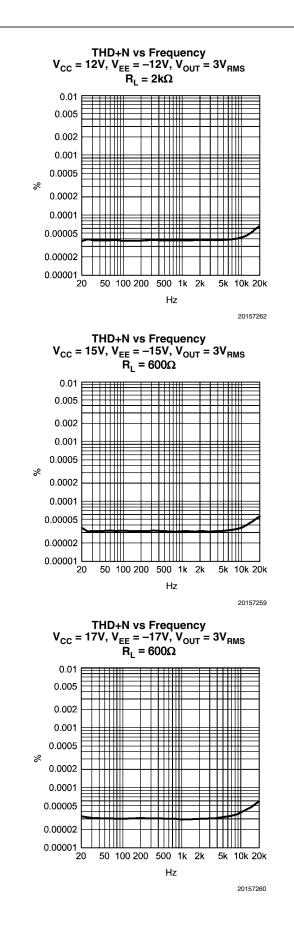
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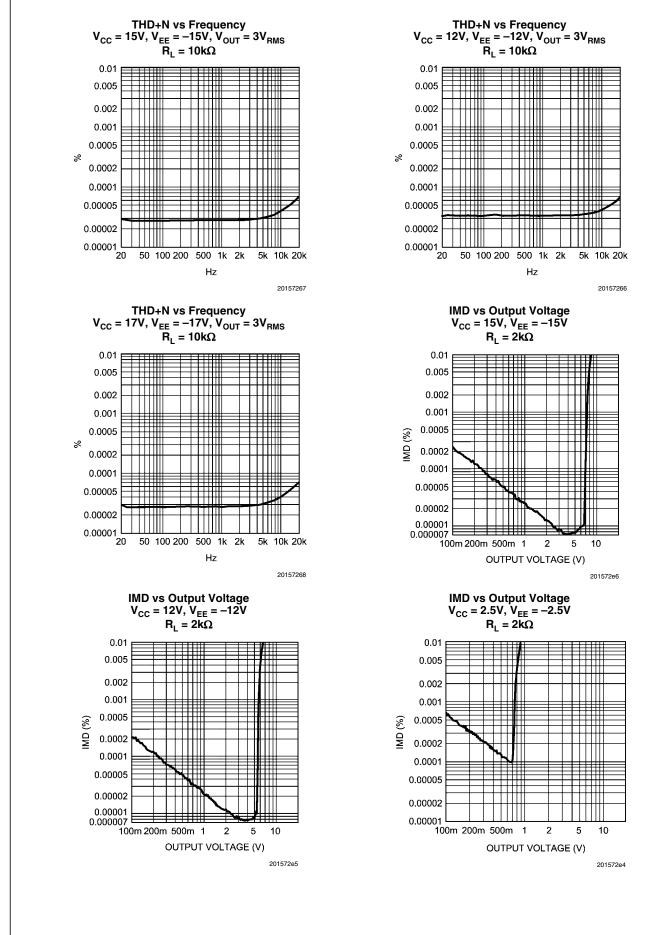






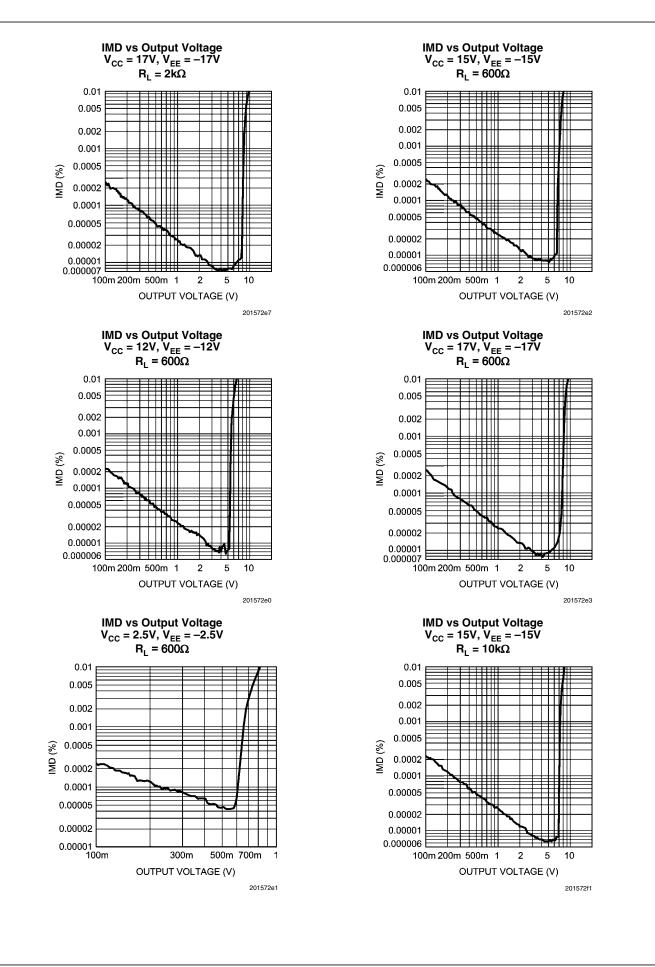
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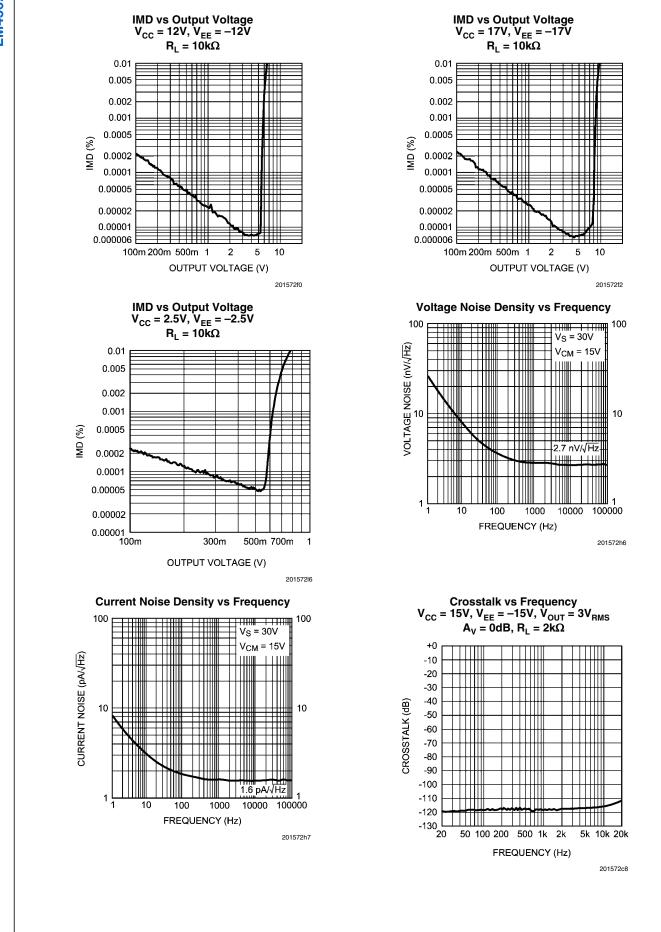




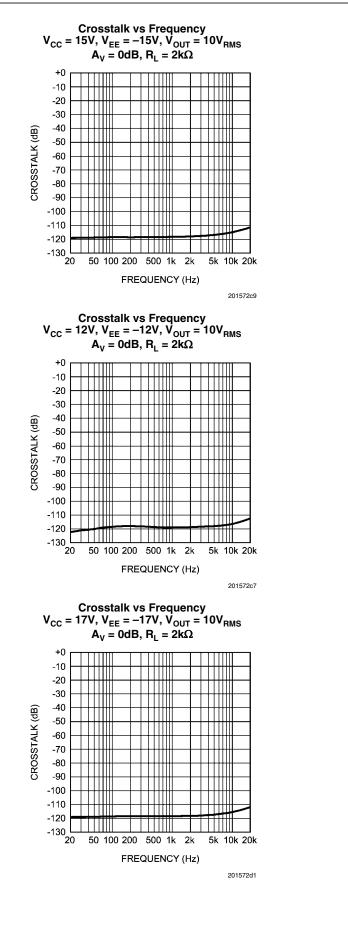
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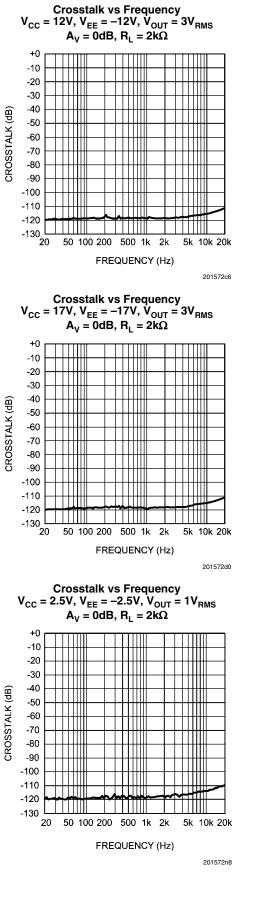


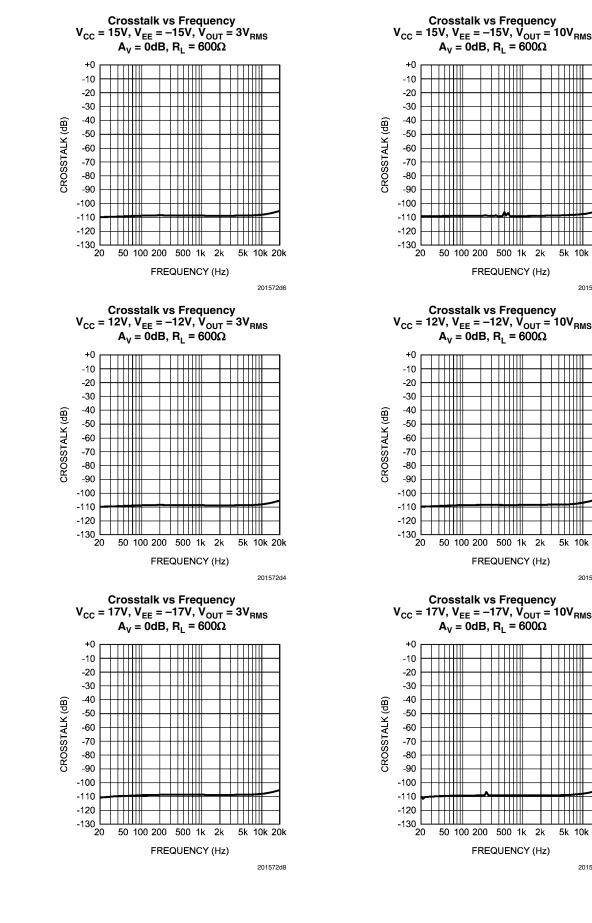




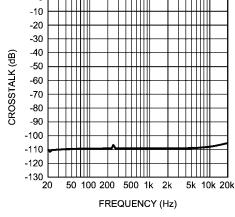






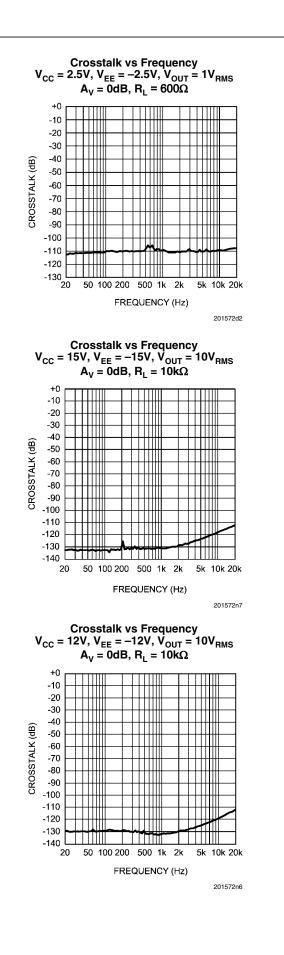


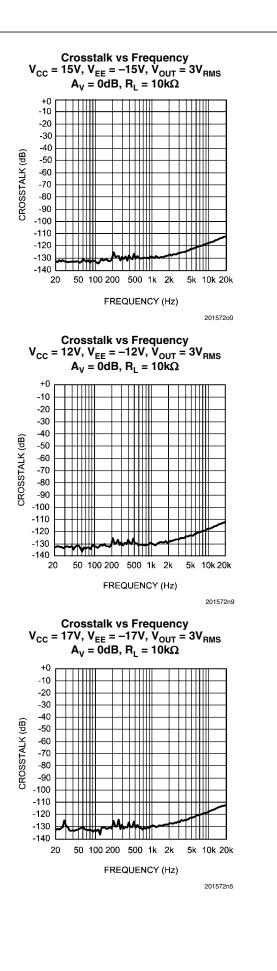
50 100 200 500 1k 2k 5k 10k 20k FREQUENCY (Hz) 201572d7 **Crosstalk vs Frequency**  $V_{CC} = 12V, V_{EE} = -12V, V_{OUT} = 10V_{RMS}$  $A_V = 0$ dB,  $R_L = 600\Omega$ 50 100 200 500 1k 2k 5k 10k 20k FREQUENCY (Hz) 201572d5 **Crosstalk vs Frequency**  $V_{CC} = 17V, V_{EE} = -17V, V_{OUT} = 10V_{RMS}$  $A_{V} = 0 dB, R_{L} = 600 \Omega$ 

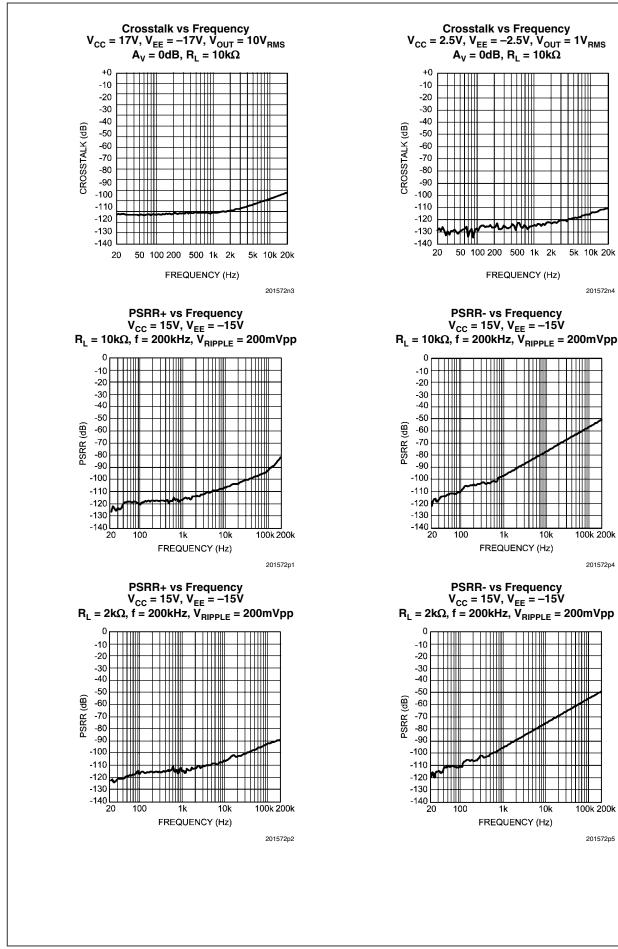


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5k 10k 20k

201572n4

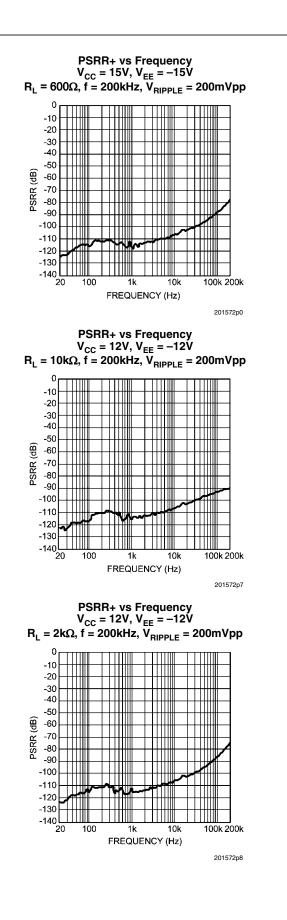
100k 200k

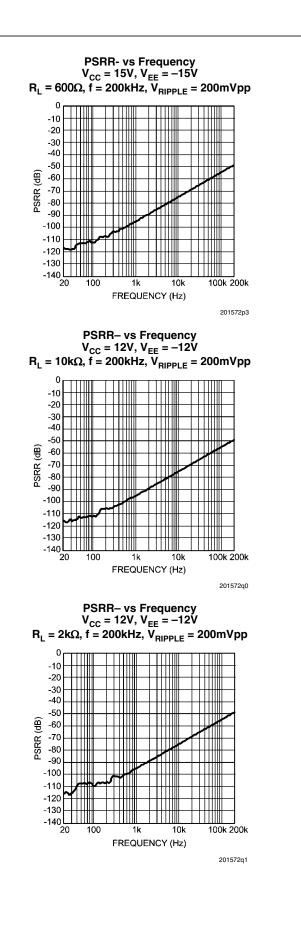
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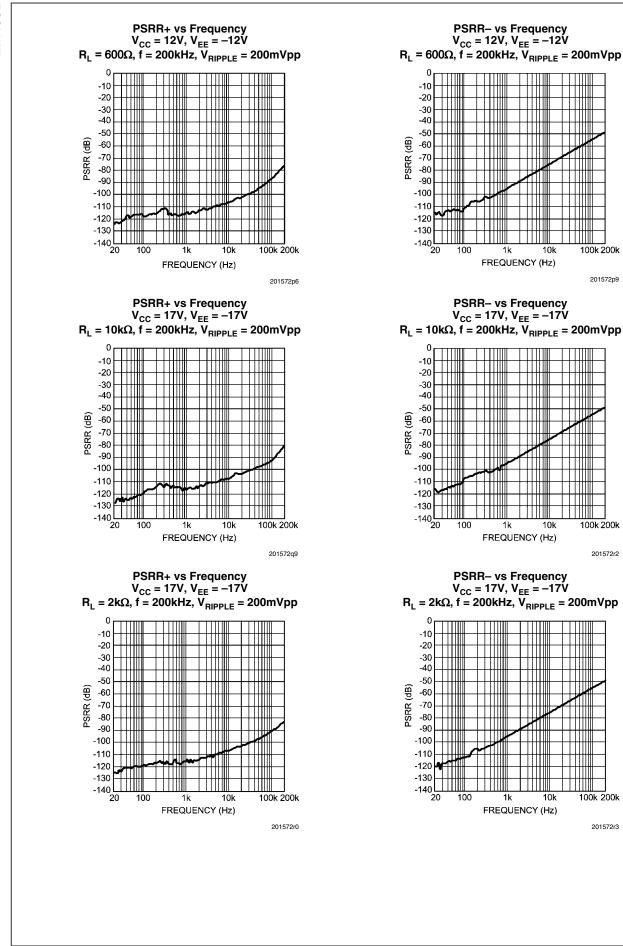
100k 200k

201572p5

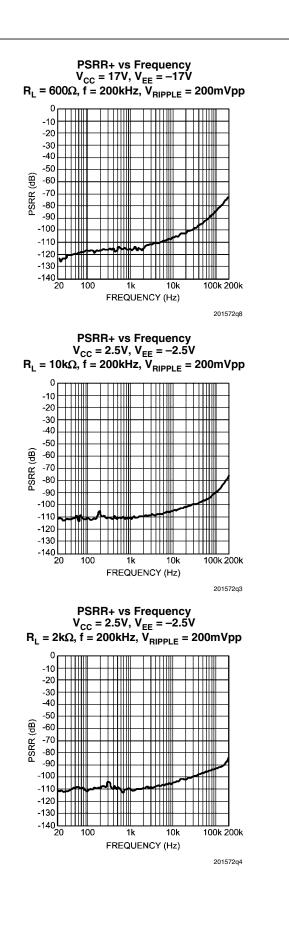


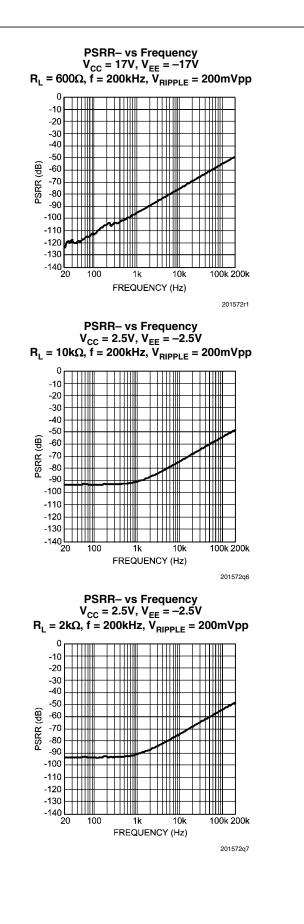


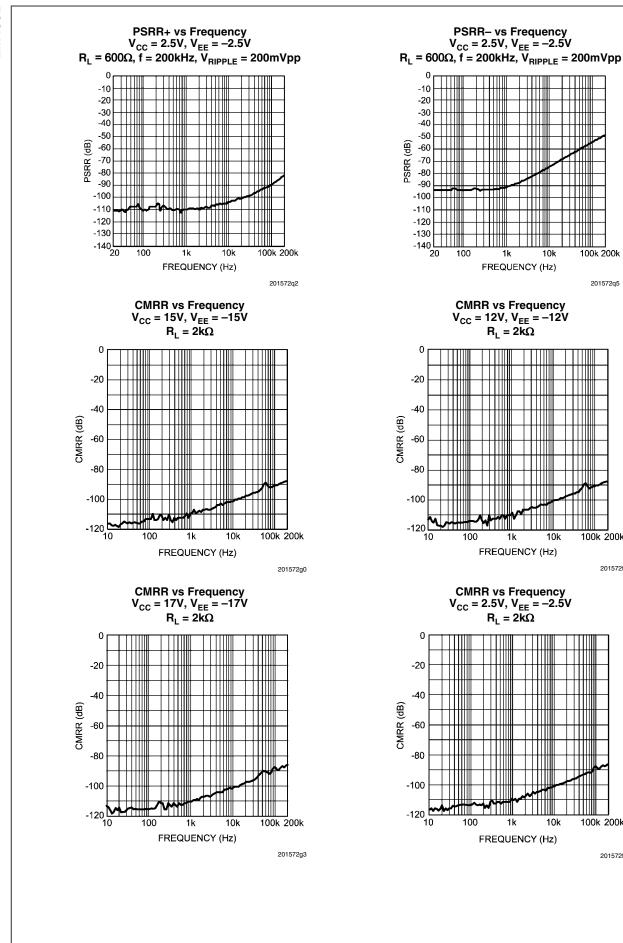












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10k

10k

100k 200k

100k 200k

201572f4

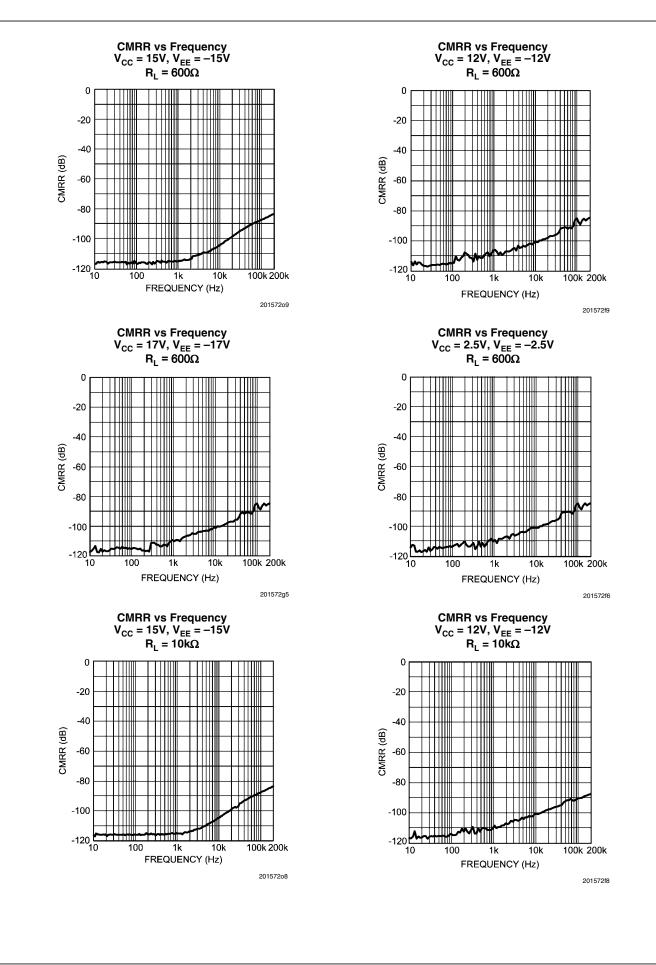
10k

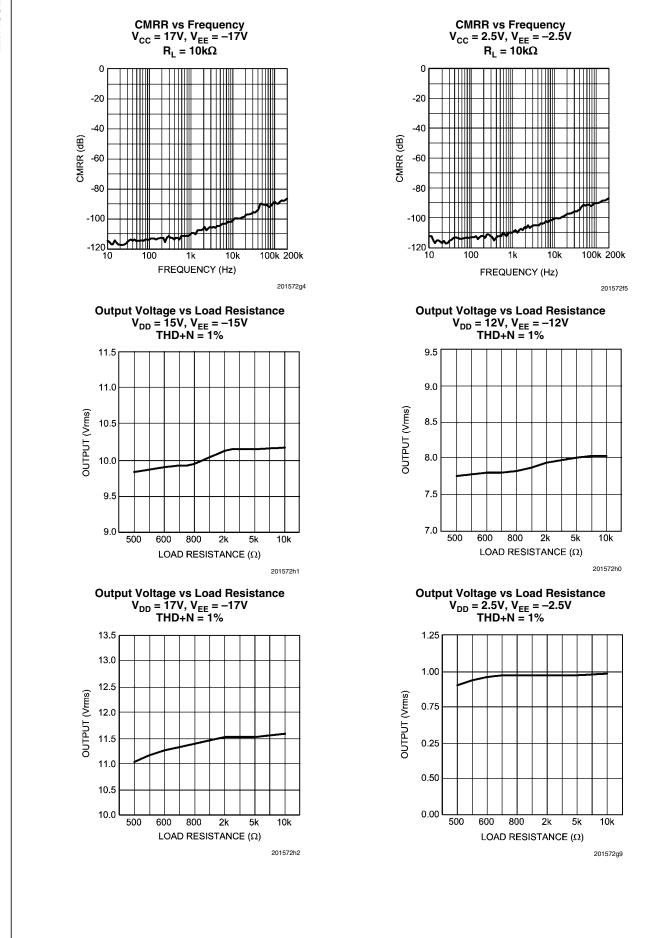
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100k 200k

201572q5

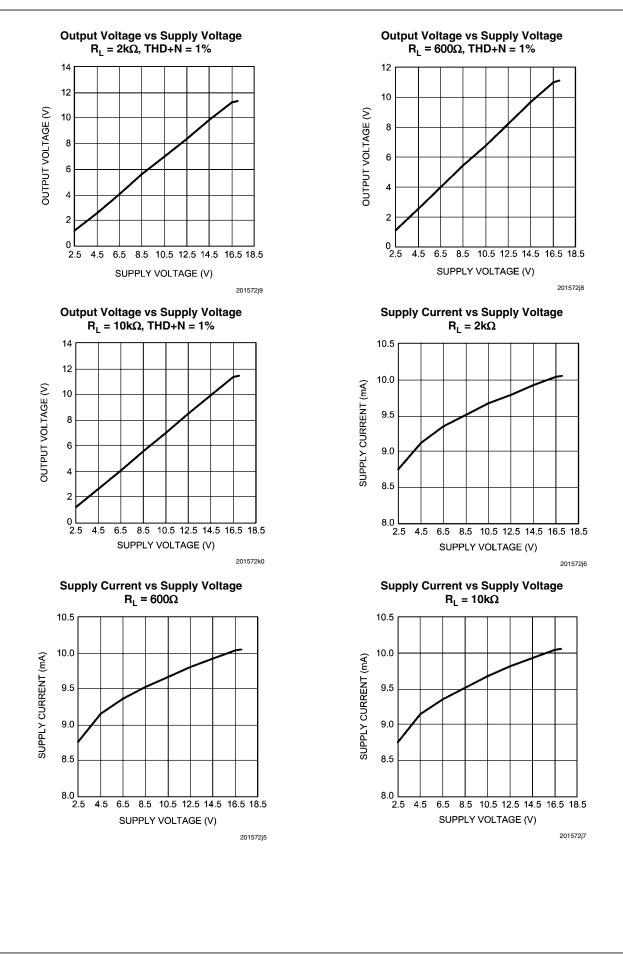




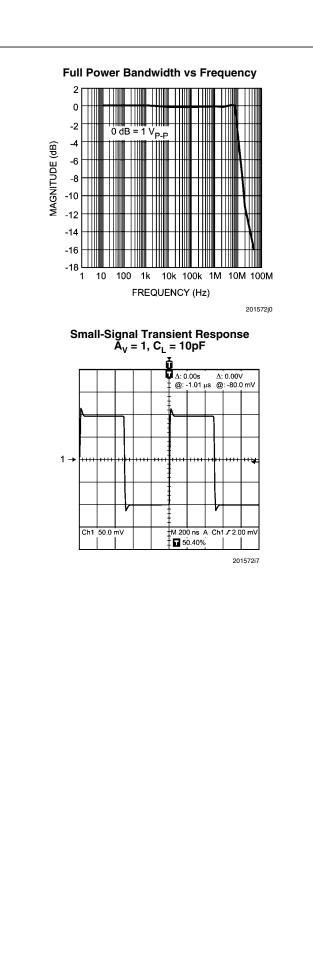


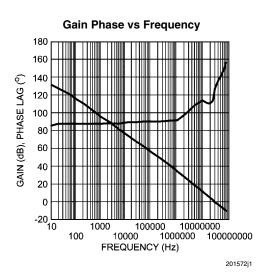
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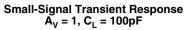


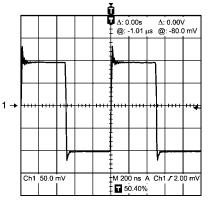


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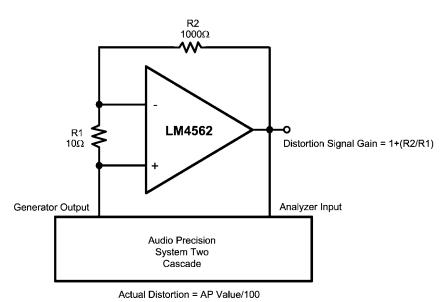
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### **DISTORTION MEASUREMENTS**

The vanishingly low residual distortion produced by LM4562 is below the capabilities of all commercially available equipment. This makes distortion measurements just slightly more difficult than simply connecting a distortion meter to the amplifier's inputs and outputs. The solution, however, is quite simple: an additional resistor. Adding this resistor extends the resolution of the distortion measurement equipment.

The LM4562's low residual distortion is an input referred internal error. As shown in Figure 1, adding the  $10\Omega$  resistor connected between the amplifier's inverting and non-inverting inputs changes the amplifier's noise gain. The result is that the error signal (distortion) is amplified by a factor of 101. Although the amplifier's closed-loop gain is unaltered, the feedback available to correct distortion errors is reduced by 101, which means that measurement resolution increases by 101. To ensure minimum effects on distortion measurements, keep the value of R1 low as shown in Figure 1.

This technique is verified by duplicating the measurements with high closed loop gain and/or making the measurements at high frequencies. Doing so produces distortion components that are within the measurement equipment's capabilities. This datasheet's THD+N and IMD values were generated using the above described circuit connected to an Audio Precision System Two Cascade.



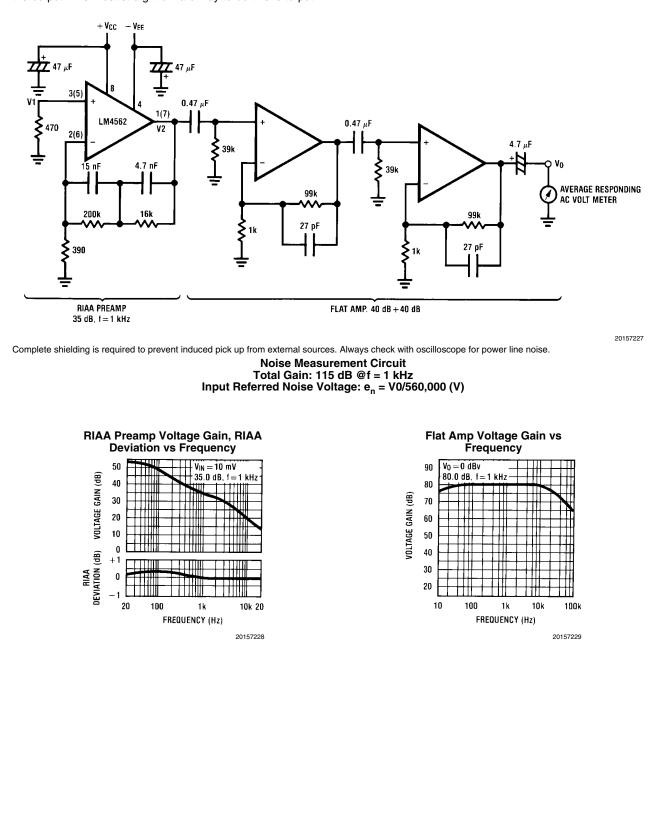
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FIGURE 1. THD+N and IMD Distortion Test Circuit

The LM4562 is a high speed op amp with excellent phase margin and stability. Capacitive loads up to 100pF will cause little change in the phase characteristics of the amplifiers and are therefore allowable.

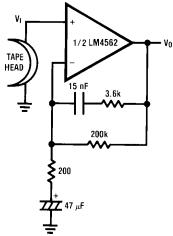
a resistor in series with the output. This resistor will also prevent excess power dissipation if the output is accidentally shorted.

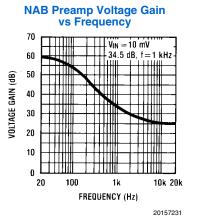
Capacitive loads greater than 100pF must be isolated from the output. The most straightforward way to do this is to put



### **TYPICAL APPLICATIONS**

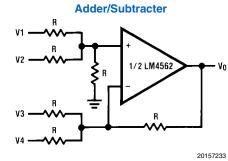


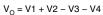




 $\begin{array}{l} A_V = 34.5\\ F = 1 \ kHz\\ E_n = 0.38 \ \mu V\\ A \ Weighted \end{array}$ 

Balanced to Single Ended Converter

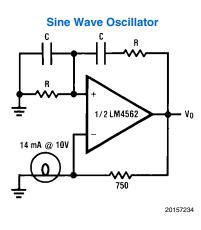




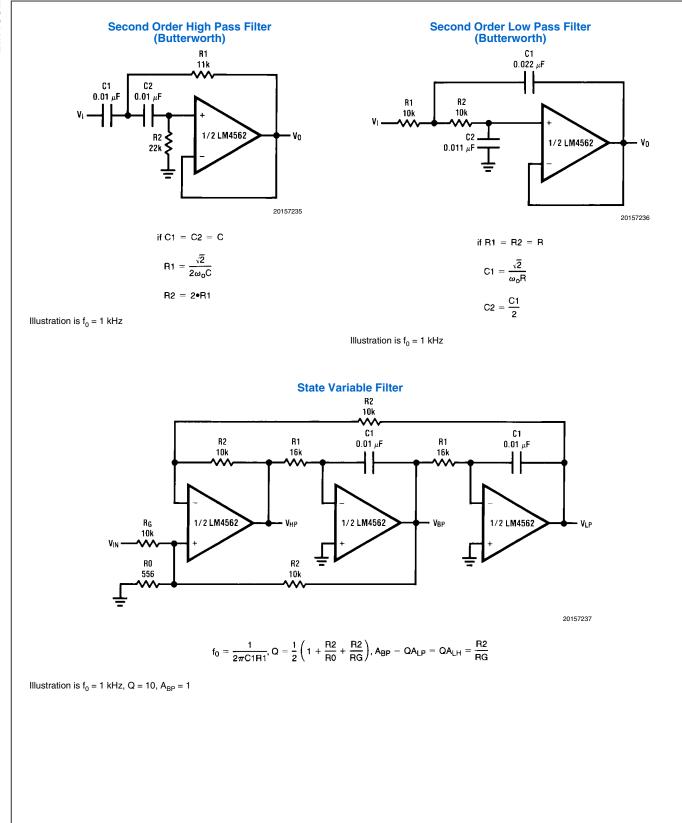
 $V_0 = V1 - V2$ 

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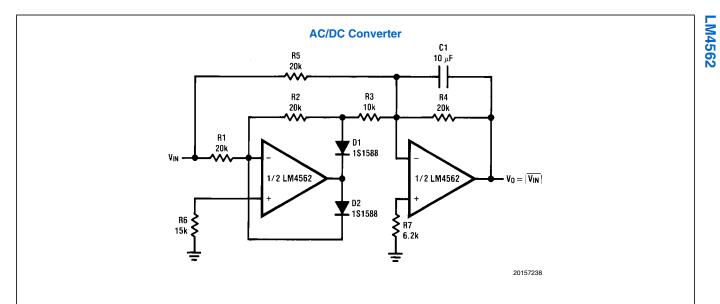




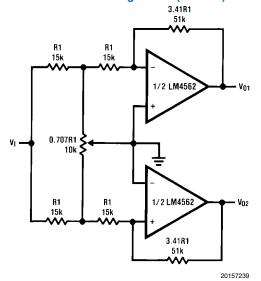


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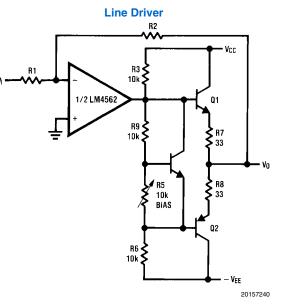
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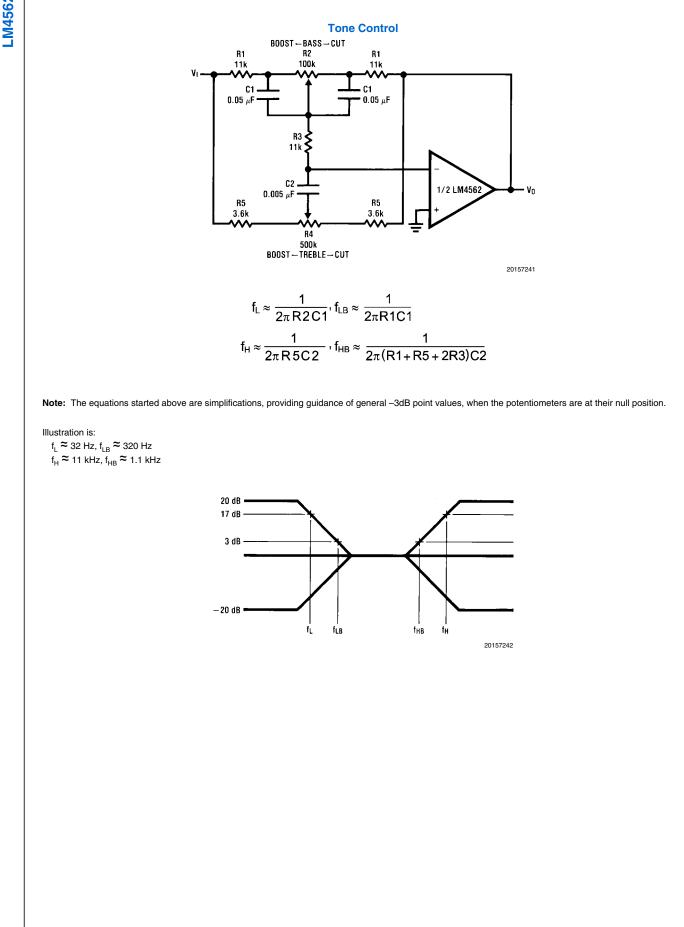


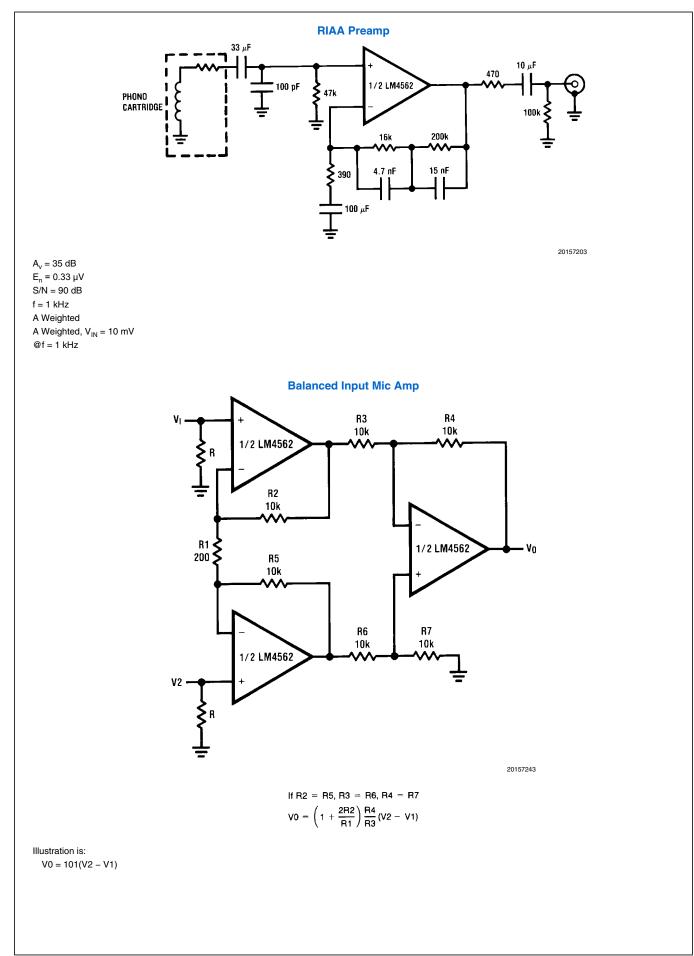


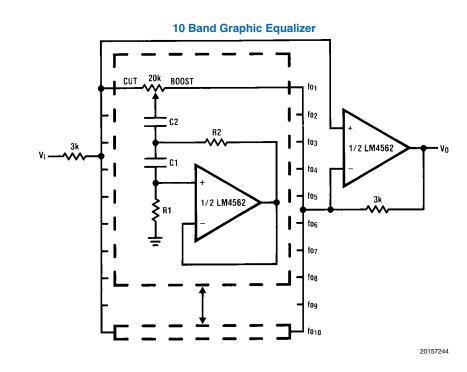
Downloaded from Elcodis.com electronic components distributor



27







fo (Hz)	C <sub>1</sub>	C <sub>2</sub>	R <sub>1</sub>	R <sub>2</sub>
32	0.12µF	4.7µF	75kΩ	500Ω
64	0.056µF	3.3µF	68kΩ	510Ω
125	0.033µF	1.5µF	62kΩ	510Ω
250	0.015µF	0.82µF	68kΩ	470Ω
500	8200pF	0.39µF	62kΩ	470Ω
1k	3900pF	0.22µF	68kΩ	470Ω
2k	2000pF	0.1µF	68kΩ	470Ω
4k	1100pF	0.056µF	62kΩ	470Ω
8k	510pF	0.022µF	68kΩ	510Ω
16k	330pF	0.012µF	51kΩ	510Ω

**Note 9:** At volume of change =  $\pm 12 \text{ dB}$ 

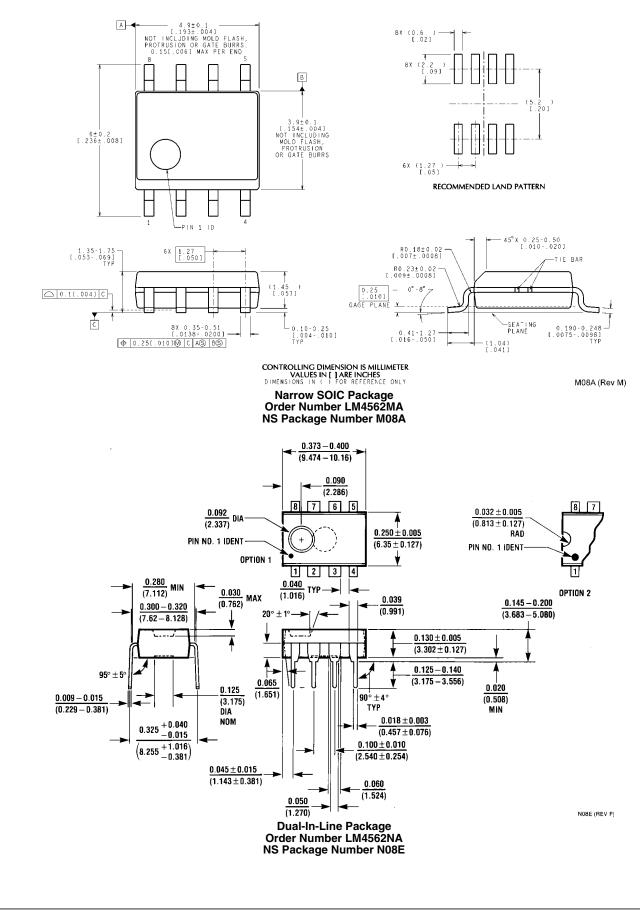
Q = 1.7

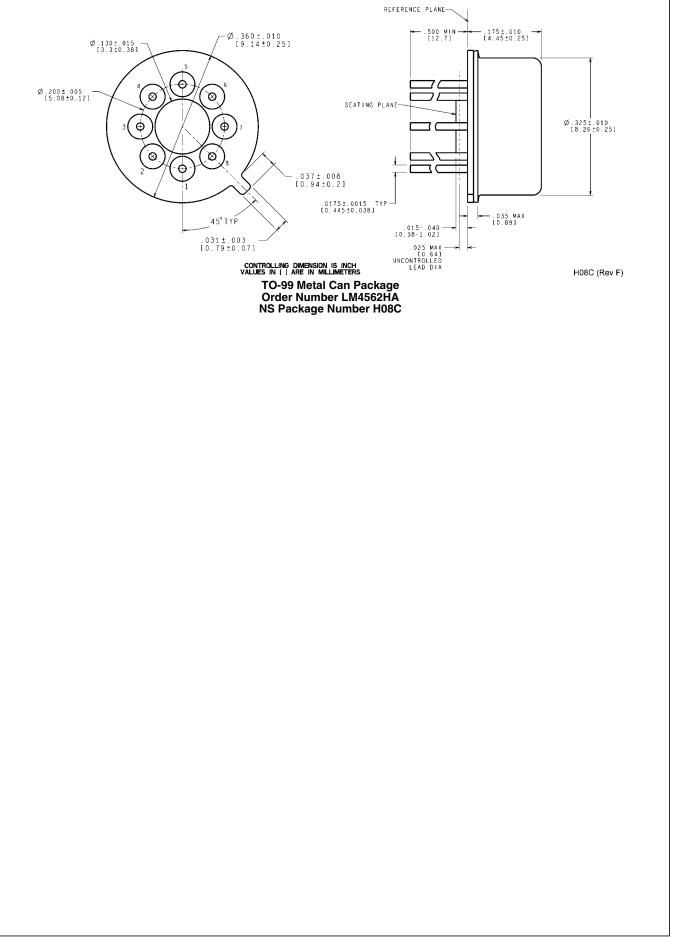
Reference: "AUDIO/RADIO HANDBOOK", National Semiconductor, 1980, Page 2-61

# **Revision History**

Rev	Date	Description	
1.0	08/16/06	Initial release.	
1.1	08/22/06	Updated the Instantaneous Short Circuit Current specification.	
1.2	09/12/06	Updated the three ±15V CMRR Typical Performance Curves.	
1.3	09/26/06	Updated interstage filter capacitor values on page 1 Typical Application schematic.	
1.4	05/03/07	Added the "general note" under the EC table.	
1.5	10/17/07	Replaced all the PSRR curves.	
1.6	01/26/10	Edited the equations on page 28 (under Tone Control).	

### Physical Dimensions inches (millimeters) unless otherwise noted





# Notes

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Data Converters	www.national.com/adc	Samples	www.national.com/samples
Interface	www.national.com/interface	Eval Boards	www.national.com/evalboards
LVDS	www.national.com/lvds	Packaging	www.national.com/packaging
Power Management	www.national.com/power	Green Compliance	www.national.com/quality/green
Switching Regulators	www.national.com/switchers	Distributors	www.national.com/contacts
LDOs	www.national.com/ldo	Quality and Reliability	www.national.com/quality
LED Lighting	www.national.com/led	Feedback/Support	www.national.com/feedback
Voltage References	www.national.com/vref	Design Made Easy	www.national.com/easy
PowerWise® Solutions	www.national.com/powerwise	Applications & Markets	www.national.com/solutions
Serial Digital Interface (SDI)	www.national.com/sdi	Mil/Aero	www.national.com/milaero
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